



Showcasing research from Dr Lihui Jia's laboratory, Institutional Center for Shared Technologies and Facilities, Institute of Geology and Geophysics, Chinese Academy of Sciences, Beijing, China.

High-accuracy analyses of key minor and trace elements in zircon by electron probe microanalysis

Minor and trace elements in zircon are informative, but high spatial resolution microanalysis techniques are urgently needed to address the limited size of zircon grains. A new EPMA method was developed in this study to determine minor and trace elements (e.g., Al, P, Ti, Y, Yb, Lu, Hf, Th, and U) in zircon with high accuracy. Detection limits can be decreased to several ppm level (3σ), and the spatial resolution in zircon analysis under 20 kV and 500 nA remains below $3\ \mu\text{m}$.

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